

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/583,870	HIKIDA ET AL.	
Examiner	Art Unit	
Cindy D. Khuu	2863	

SEARCHED					
Class	Subclass	Date	Examiner		
702	92	12/14/2007	СНК		
702	95	12/13/2007	СНК		
702	150	12/12/2007	СНК		
702	94	12/14/2007	СНК		
			•		

INTERFERENCE SEARCHED					
Subclass	Date	Examiner			
92,94,95	12/14/2007	снк			
150	12/13/2007	СНК			
*	12/13/2007	CHK			
	Subclass 92,94,95	Subclass Date   92,94,95 12/14/2007   150 12/13/2007			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
USPTO East Databases: USPGPUB, USPAT, EPO, JPO, DERWENT, IBM_TDB. (Text Only)	12/14/2007	СНК		
Plus Search .	12/13/2007	СНК		
702/92,94,95 and 150	12/14/2007	СНК		
	1			